ABSTRACT OF THE DISCLOSURE

A circuit arrangement (100) for controlling a first terminal and a second terminal of a preferably contactless integrated circuit, particularly for testing a CMOS circuit, tests a multitude of integrated circuits simultaneously while using a low-cost structure. The circuit arrangement permits a simple write/read unit assigned to the integrated circuit, and enables the simultaneous testing of a multitude of integrated circuits using a low-cost structure.

V

[]

LII